

Supporting Information

Title

Surface Chemistry and Restructuring in Thin-Film $\text{La}_{n+1}\text{Ni}_n\text{O}_{3n+1}$ ($n = 1, 2$ and 3) Ruddlesden-Popper Oxides

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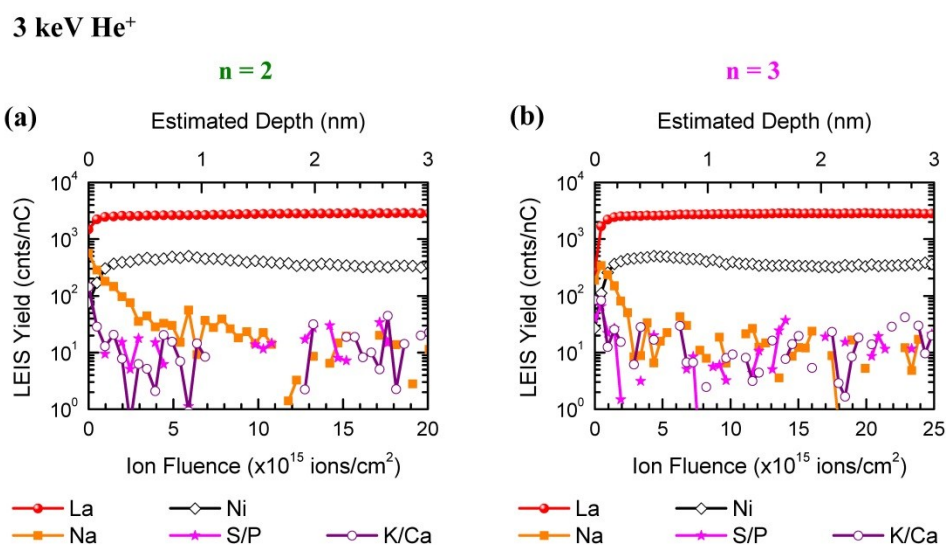


Figure S1 LEIS depth profiles of annealed (a) $\text{La}_3\text{Ni}_2\text{O}_{7-\delta}$ and (b) $\text{La}_4\text{Ni}_3\text{O}_{10-\delta}$ epitaxial films obtained from the LEIS yield of La/Ni cations and adsorbed contaminants (Na, S, P, K and Ca) using the 3 keV He⁺ analysis beam at the surface and near-surface region.